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With the principle of "Quality Parts, Customers Priority, Honest Operation, and Considerate Service", our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip, ALPS, ROHM, Xilinx, Pulse, ON, Everlight and Freescale. Main products comprise IC, Modules, Potentiometer, IC Socket, Relay, Connector. Our parts cover such applications as commercial, industrial, and automotives areas.

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600V APT150GN60J

Utilizing the latest Field Stop and Trench Gate technologies, these IGBT's have ultra low $V_{\text{CE}(ON)}$ and are ideal for low frequency applications that require absolute minimum conduction loss. Easy paralleling is a result of very tight parameter distribution and a slightly positive $V_{\text{CE}(ON)}$ temperature coefficient. A built-in gate resistor ensures extremely reliable operation, even in the event of a short circuit fault. Low gate charge simplifies gate drive design and minimizes losses.

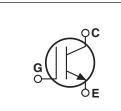


• 600V Field Stop

• Trench Gate: Low V_{CE(on)}

Easy Paralleling

Intergrated Gate Resistor: Low EMI, High Reliability



Applications: Welding, Inductive Heating, Solar Inverters, SMPS, Motor drives, UPS

MAXIMUM RATINGS

All Ratings: T_C = 25°C unless otherwise specified.

Symbol	Parameter	APT150GN60J	UNIT	
V _{CES}	Collector-Emitter Voltage	600	Volts	
V _{GE}	Gate-Emitter Voltage	±30		
I _{C1}	Continuous Collector Current @ T _C = 25°C	220		
I _{C2}	Continuous Collector Current @ T _C = 110°C	123	Amps	
I _{CM}	Pulsed Collector Current ①	450		
SSOA	Switching Safe Operating Area @ T _J = 175°C	450A @ 600V		
P_{D}	Total Power Dissipation	536	Watts	
T_J , T_{STG}	Operating and Storage Junction Temperature Range	-55 to 175		
T _L	Max. Lead Temp. for Soldering: 0.063" from Case for 10 Sec.	300	°C	

STATIC ELECTRICAL CHARACTERISTICS

Symbol	Characteristic / Test Conditions	MIN	TYP	MAX	Units
V _{(BR)CES}	Collector-Emitter Breakdown Voltage $(V_{GE} = 0V, I_C = 4mA)$	600			Volts
V _{GE(TH)}	Gate Threshold Voltage $(V_{CE} = V_{GE}, I_{C} = 2400\mu\text{A}, T_{j} = 25^{\circ}\text{C})$	5.0	5.8	6.5	
V _{CE(ON)}	Collector-Emitter On Voltage $(V_{GE} = 15V, I_{C} = 150A, T_{j} = 25^{\circ}C)$	1.05	1.45	1.85	
	Collector-Emitter On Voltage $(V_{GE} = 15V, I_C = 150A, T_j = 125^{\circ}C)$		1.65		
I _{CES}	Collector Cut-off Current $(V_{CE} = 600V, V_{GE} = 0V, T_j = 25^{\circ}C)$ (2)			25	μA
	Collector Cut-off Current (V _{CE} = 600V, V _{GE} = 0V, T _j = 125°C) ⁽²⁾			TBD	
I _{GES}	Gate-Emitter Leakage Current (V _{GE} = ±20V)			600	nA
R _{G(int)}	Intergrated Gate Resistor		2		Ω

CAUTION: These Devices are Sensitive to Electrostatic Discharge. Proper Handling Procedures Should Be Followed.

Symbol	Characteristic	Test Conditions	MIN	TYP	MAX	UNIT
C _{ies}	Input Capacitance	Capacitance		9200		
C _{oes}	Output Capacitance	$V_{GE} = 0V, \ V_{CE} = 25V$		350		рF
C _{res}	Reverse Transfer Capacitance	f = 1 MHz		300		
V _{GEP}	Gate-to-Emitter Plateau Voltage	Gate Charge		9.5		V
Q_g	Total Gate Charge ^③	V _{GE} = 15V		970		
Q _{ge}	Gate-Emitter Charge	V _{CE} = 300V		65		nC
Q _{gc}	Gate-Collector ("Miller") Charge	I _C = 150A		510		
SSOA	Switching Safe Operating Area	$T_J = 175^{\circ}\text{C}, R_G = 4.3\Omega^{\textcircled{7}}, V_{GE} = 15\text{V}, L = 100\mu\text{H}, V_{CE} = 600\text{V}$	450			А
t _{d(on)}	Turn-on Delay Time	Inductive Switching (25°C)		44		
t _r	Current Rise Time	V _{CC} = 400V		110		
t _{d(off)}	Turn-off Delay Time	V _{GE} = 15V		430		ns
t _f	Current Fall Time	I _C = 150A		60		
E _{on1}	Turn-on Switching Energy ⁴	$R_{G} = 1.0\Omega^{\bigcirc}$		8810		
E _{on2}	Turn-on Switching Energy (Diode) ^⑤	T _J = +25°C		8615		μJ
E _{off}	Turn-off Switching Energy ^⑥			4295		
t _{d(on)}	Turn-on Delay Time	Inductive Switching (125°C)		44		
t _r	Current Rise Time	V _{CC} = 400V		110		ns
t _{d(off)}	Turn-off Delay Time	V _{GE} = 15V		480		115
t _f	Current Fall Time	I _C = 150A		95		
E _{on1}	Turn-on Switching Energy ⁴	$R_G = 1.0\Omega^{\bigcirc}$		8880		
E _{on2}	Turn-on Switching Energy (Diode) ^⑤	$T_{J} = +125^{\circ}C$		9735		μJ
E _{off}	Turn-off Switching Energy ^⑥]		5460		

THERMAL AND MECHANICAL CHARACTERISTICS

Symbol	Characteristic	MIN	TYP	MAX	UNIT	
$R_{\theta JC}$	Junction to Case (IGBT)			0.28 °C/W		
$R_{ heta JC}$	Junction to Case (DIODE)			N/A	C/VV	
V _{Isolation}	RMS Voltage (50-60Hz Sinusoidal Waveform from Terminals to Mounting Base for 1 Min.)	2500			Volts	
W _T	Package Weight		1.03		oz	
			29.2		gm	
Torque	Maximum Terminal & Mounting Torque			10	lb•in	
				1.1	N•m	

- 1 Repetitive Rating: Pulse width limited by maximum junction temperature.
- 2 For Combi devices, \textbf{I}_{ces} includes both IGBT and FRED leakages
- ③ See MIL-STD-750 Method 3471.
- (4) E_{on1} is the clamped inductive turn-on energy of the IGBT only, without the effect of a commutating diode reverse recovery current adding to the IGBT turn-on loss. Tested in inductive switching test circuit shown in figure 21, but with a Silicon Carbide diode.
- (5) E_{on2} is the clamped inductive turn-on energy that includes a commutating diode reverse recovery current in the IGBT turn-on switching loss. (See Figures 21, 22.)
- 6 E_{off} is the clamped inductive turn-off energy measured in accordance with JEDEC standard JESD24-1. (See Figures 21, 23.)
- \bigcirc R_G is external gate resistance, not including R_{G(int)} nor gate driver impedance. (MIC4452)

TYPICAL PERFORMANCE CURVES

APT150GN60J

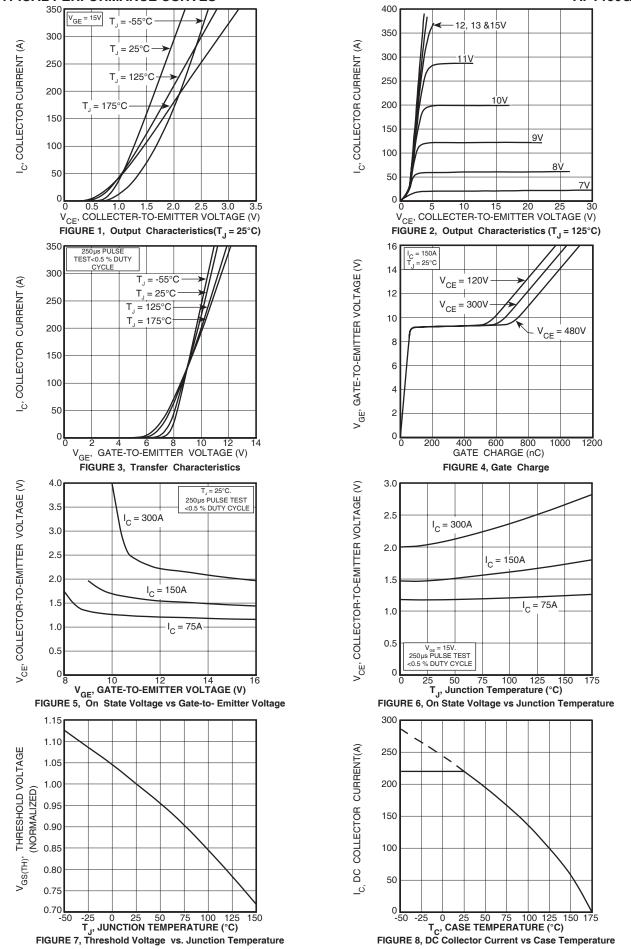
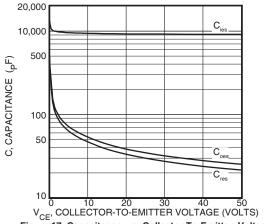


FIGURE 16, Switching Energy Losses vs Junction Temperature

FIGURE 15, Switching Energy Losses vs. Gate Resistance

TYPICAL PERFORMANCE CURVES



APT150GN60J

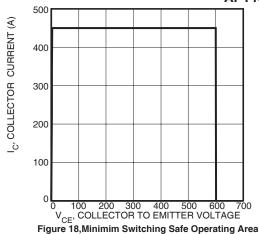
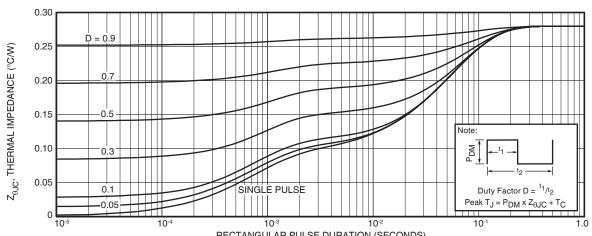


Figure 17, Capacitance vs Collector-To-Emitter Voltage



RECTANGULAR PULSE DURATION (SECONDS)
Figure 19a, Maximum Effective Transient Thermal Impedance, Junction-To-Case vs Pulse Duration

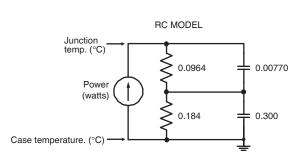


FIGURE 19b, TRANSIENT THERMAL IMPEDANCE MODEL

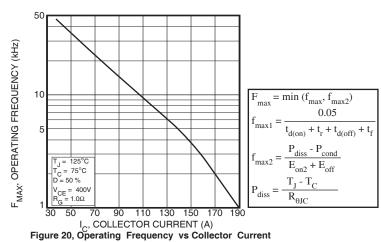


Figure 21, Inductive Switching Test Circuit

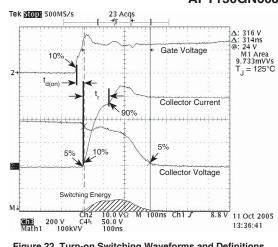


Figure 22, Turn-on Switching Waveforms and Definitions

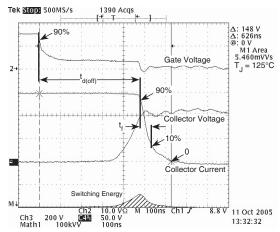


Figure 23, Turn-off Switching Waveforms and Definitions

SOT-227 (ISOTOP®) Package Outline

